Search Notes		

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
10/646,725	IWANO, HIROTAKA	
Examiner	Art Unit	
Son M. Tang	2612	

SEARCHED			
Class	Subclass	Date	Examiner
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
340/103-104,199,435-438 382/104,209,103 180/167-169 701/\$.ccls. Text only	9/4/2006	TANG
Benjamin Lee	9/4/2006	TANG
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